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# RELIABILITY ASSESSMENT OF RECONFIGURABLE FLIGHT CONTROL SYSTEMS USING SURE AND ASSIST<sup>1</sup>

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## ● OBJECTIVES

○ DEVELOP RELIABILITY ASSESSMENT TOOLS

\*SOPHISTICATED SYSTEM CONFIGURATION

\*MULTIPLE SOURCES OF UNCERTAINTY

○EVALUATE THE APPLICABILITY OF SURE<sup>[4]</sup> AND ASSIST<sup>[2]</sup>

\***SURE: SEMI-MARKOV UNRELIABILITY RANGE EVALUATOR**

—APPLICABLE TO A LARGE CLASS OF SEMI-MARKOV MODELS

—EFFICIENT AND ACCURATE

—AVAILABLE FOR VMS/UNIX/MS-WINDOWS OS<sup>1</sup>

\***ASSIST: ABSTRACT SEMI-MARKOV SPECIFICATION INTERFACE TO THE  
SURE TOOL**

MODEL GENERATION TOOL FOR DIRECT INTERFACE WITH **SURE**

—POWERFUL AID TO MODELING COMPLEX SEMI-MARKOV PROCESSES

—AVAILABLE FOR VMS/UNIX/MS-DOS OS<sup>1</sup>

\*JUSTIFICATION FOR FURTHER COMPUTATION SIMPLIFICATIONS

—ON-LINE DECISIONS

—UTILITY

<sup>1</sup>Support by the NASA under Cooperative Agreement NCC-1-336, and by the ASEE  
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Thanks to Ricky Butler and Allan White for their time and insightful suggestions.

- SOME BACKGROUND

- MARKOV PROCESS<sup>[7]</sup>:

$\{X(t) \mid t \in (0, \infty)\}$  IS A MARKOV PROCESS IF  $\forall t_0 < t_1 \dots < t_n < t$ , THE CONDITIONAL DISTRIBUTION OF  $X(t)$  FOR GIVEN VALUES OF  $X(t_0), \dots, X(t_n)$  DEPENDS ONLY ON  $X(t_n)$

$$P(X(t) \leq x \mid X(t_n) = x_n, \dots, X(t_0) = x_0) = P(X(t) \leq x \mid X(t_n) = x_n)$$

- \* HOMOGENEOUS MARKOV PROCESS:

$$P(X(t) \leq x \mid X(t_n) = x_n) = P(X(t - t_n) \leq x \mid X(0) = x_n)$$

- WHITE'S INTERPRETATION:

CONSTANT RATE

INDEPENDENT COMPETING EVENTS

INDEPENDENT SEQUENTIAL EVENTS

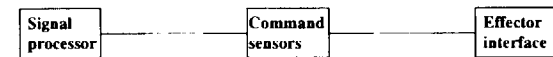
$\Rightarrow$

$F(t)$  (TIME A PROCESS SPENDS IN A STATE) IS EXPONENTIAL

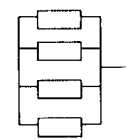
$$P(T \leq t) = F(t) = 1 - e^{-F'(0)t}$$

\* SEMI-MARKOV PROCESS: A MARKOV PROCESS WHOSE DISTRIBUTION IS NOT EXPONENTIAL

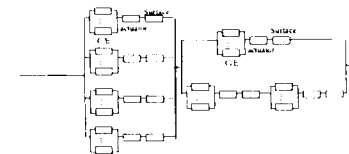
- EXAMPLE: AFTI/F-16 FAULT TOLERANT FCS<sup>[10]</sup>



**Functional dependency of subsystems in the FTFCS**



**Standard**



**Less standard**

- A PARALLEL-TO-SERIES INTERCONNECTION OF 5 BLOCKS

- \* FLIGHT CRITICAL PROCESSORS

—POWER SUPPLIES, DIGITAL PROCESSORS

- \* I/O CONTROL MODULE

- \* PILOT COMMAND SENSOR

- \* AIRCRAFT STATE SENSOR

- \* EFFECTOR

---ACTUATORS, SURFACES, INTERFACE UNITS

- SOME PROPERTIES OF THE RELIABILITY MODEL
  - BUILDING BLOCKS: SUBSYSTEMS (NO SPARES, NO REPAIRS)
  - REDUNDANCY TYPE: HARDWARE AND FUNCTIONAL
  - FAILURE: CONTROL PERFORMANCE DEPENDENT
    - SUBSYSTEM FAILURE
      - LACK OF REDUNDANT CONTROL AUTHORITY
  - FAILURE DETECTION: RESIDUE BASED
    - RESIDUALS ARE NOISY
    - RECONFIGURATION DECISIONS INVOLVE RISKS
  - MISSION TIME  $t_m$ : SHORT
  - HOLDING TIME DISTRIBUTION  $F(t)$ : DIFFICULT TO DETERMINE
    - NO BASIS FOR ASSUMING EXPONENTIAL
    - POSSIBLE TO BOUND BY EXPONENTIAL DISTRIBUTIONS

$$1 - e^{-\lambda_l t} \leq F(t) \leq 1 - e^{-\lambda_u t}, \quad t \leq t_m$$

- WHAT TO EXPECT?
  - RIGHT ORDERS OF MAGNITUDE

- PROPERTIES (CONT'D) PECULIAR TO FUNCTIONAL REDUNDANCY
  - SYSTEM ARCHITECTURE: MORE COMPLEX IN GENERAL
    - \* LESS SYMMETRY  $\Rightarrow$  HARDER TO OBTAIN A RELIABILITY MODEL
  - DEATH STATE: DICTATED BY RELIABILITY REQUIREMENTS
    - \* INOPERATIVE WITH MAJORITY
    - \* OPERATIVE WITHOUT MAJORITY
    - \* NO.1 CAUSE OF DEATH  $\Rightarrow$  UNSUCCESSFUL RECONFIGURATION
      - FALSE ALARM
      - MISS DETECTION
      - FALSE IDENTIFICATION
      - FALSE RECONFIGURATION
  - \* EXHAUSTION OF FUNCTIONAL REDUNDANCY
  - COVERAGE  $C(t)$ : NECESSARY
    - \* HIGHLY SCENARIO DEPENDENT;
    - \* VERY DIFFICULT TO ESTIMATE;
    - \* HIGHLY TIME DEPENDENT;
    - \* HARD TIME LIMIT ( $t_{max} < \text{DEPARTURE TIME}$ )

$$C(t) \approx C(t_{max})$$

- AN EXAMPLE OF CALCULATED COVERAGE

- SCENARIO — 75% LOSS OF CANARD EFFECTIVENESS

- DATA

- MODEL OF THE AIRCRAFT

MEASURED ANGLE OF ATTACK AND PITCH ANGLE

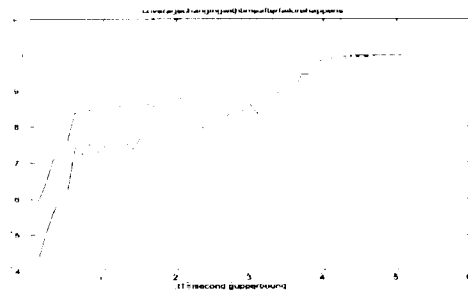
- FACTORS AFFECTING THE VALUE OF COVERAGE

- PERFORMANCE OF CONTROL, DIAGNOSTIC, DECISION MODULES

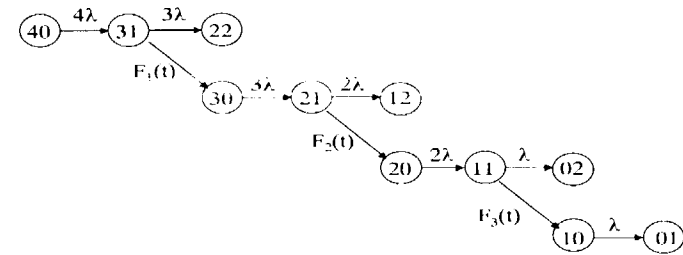
- RESULTS

- A LUCKY SITUATION OF ACHIEVING 0.9999 AFTER 4.2 SECONDS

- AT T=0.5S, LOWER BOUND OF COVERAGE IS ONLY 0.75

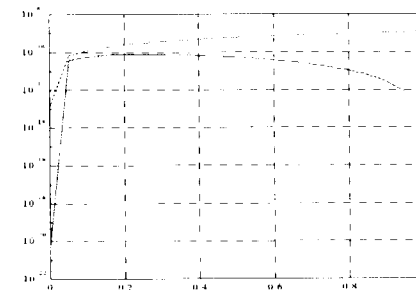


- RELIABILITY ANALYSIS OF THE PROCESSOR BLOCK



Semi-Markov process:  
Degradable 4-plex with full reconfiguration

- BLOCK FAILURE PROBABILITY BOUNDS



$$\lambda = 10^{-5}$$

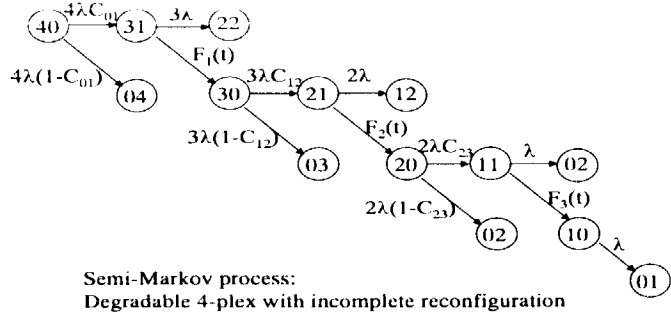
$$\mu \in [10^{-4}, 10^0]$$

$$\sigma = 10^{-2}$$

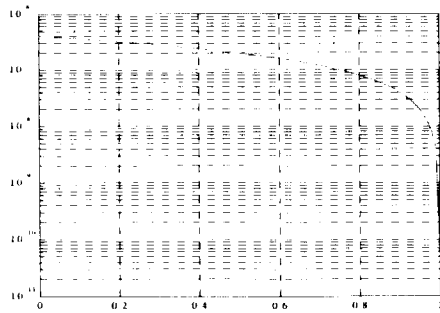
$$C_{01} = C_{12} = C_{23} = 1$$

$$t_m = 1$$

- RELIABILITY ANALYSIS OF THE PROCESSOR BLOCK  
RECONFIGURATION IS NOT COMPLETE



- BLOCK FAILURE PROBABILITY BOUNDS



$$\lambda = 10^{-5}$$

$$\mu = 10^{-1}$$

$$\sigma = 10^{-2}$$

$$C_{01} \in [0.99, 1.0]$$

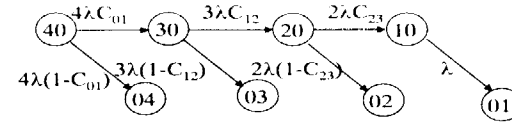
$$C_{12} \in [0.95, 1.0]$$

$$C_{23} \in [0.90, 1.0]$$

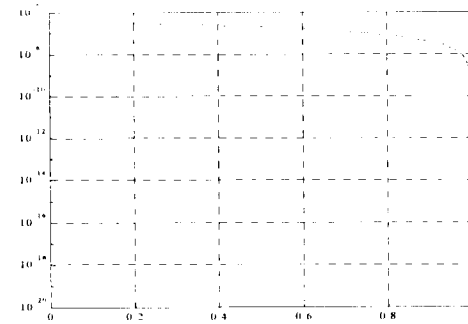
$$t_m = 1$$

- SURE RELIABILITY ANALYSIS OF THE PROCESSOR BLOCK  
—INSTANTANEOUS REMOVAL OF A FAULTY SUBSYSTEM

Markov process:  
Degradable 4-plex with incomplete reconfiguration



- BLOCK FAILURE PROBABILITY BOUNDS



$$\lambda = 10^{-5}$$

$$\mu = 0.0$$

$$C_{01} \in [0.99, 1.0]$$

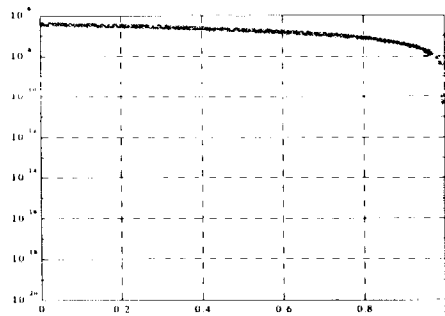
$$C_{12} \in [0.95, 1.0]$$

$$C_{23} \in [0.90, 1.0]$$

$$t_m = 1$$

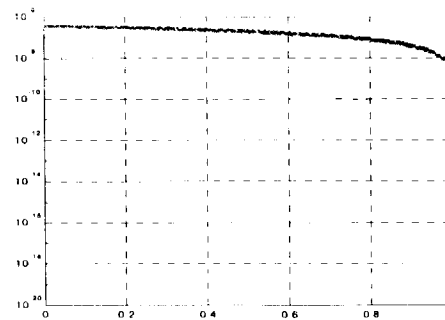
- EFFECTS OF NEGLECTING REMOVAL TIMES

- BLOCK FAILURE PROBABILITY BOUNDS



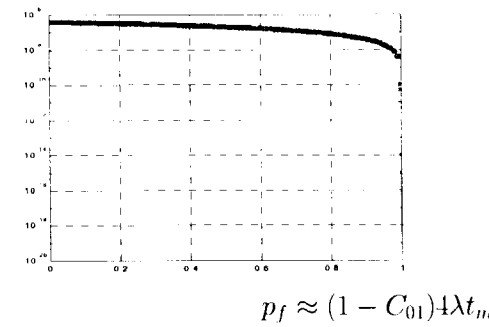
$$\begin{aligned}\lambda &= 10^{-5} \\ \mu &= 10^{-1} \\ C_{01} &\in [0.99, 1.0] \\ C_{12} &\in [0.95, 1.0] \\ C_{23} &\in [0.90, 1.0] \\ t_m &= 1\end{aligned}$$

- BLOCK FAILURE PROBABILITY



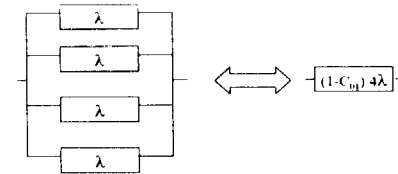
$$\begin{aligned}\lambda &= 10^{-5} \\ \mu &= 10^4 \\ C_{01} &\in [0.99, 1.0] \\ C_{12} &\in [0.95, 1.0] \\ C_{23} &\in [0.90, 1.0] \\ t_m &= 1\end{aligned}$$

- FURTHER SIMPLIFICATION OF THE PROCESSOR MODEL



$$p_f \approx (1 - C_{01})4\lambda t_m$$

- A SYSTEM WITH AN EQUIVALENT FIRST ORDER EFFECT

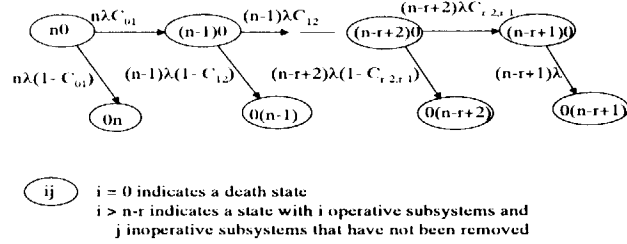


- VALID IF RELATIVE TO THE FAILURE PROCESS

- REMOVAL OF FAULTY SUBSYSTEMS IS FAST
- MISSION TIME IS SHORT

- JUSTIFICATION OF 2ND APPROXIMATION

- AN  $r + 1$ -STATE MARKOV PROCESS



- FAILURE OF AN  $n$ -SUBSYSTEM BLOCK

- $r$  OR MORE FAILED SUBSYSTEMS, OR
- INCORRECT RECONFIGURATION DECISION

- SOME NOTATIONS

- $\lambda$ : FAILURE RATE OF A SUBSYSTEM
- $t_m$ : MISSION TIME
- $p_{ij}(t)$ : TRANSITION PROBABILITY
- $C_{ij}$ : COVERAGE OF A TRANSITION

- COMBINATORY APPROACH

$$P(t) \equiv \begin{bmatrix} p_{00}(t) & p_{01}(t) & p_{02}(t) & \cdots & p_{0r}(t) \\ 0 & p_{11}(t) & p_{12}(t) & \cdots & p_{1r}(t) \\ 0 & 0 & p_{22}(t) & \cdots & p_{2r}(t) \\ \vdots & & & & \vdots \\ 0 & \cdots & & 0 & p_{rr}(t) \end{bmatrix}$$

$$p_{ij}(t) = \binom{n-i}{j-i} q^{j-i}(t) (1-q(t))^{n-i} C_{ij}, \quad i \leq j < r$$

$$p_{ij}(t) = 0, \quad i > j$$

$$p_{ir}(t) = 1 - \sum_{j=i}^{r-1} p_{ij}(t), \quad 0 \leq i \leq r-1$$

$$p_{rr}(t) = 1$$

where

$$q(t) = (1 - e^{-\lambda t})$$

IS THE SUBSYSTEM FAILURE PROBABILITY

- TRANSITION RATE MATRIX  $Q \equiv \dot{P}(0)$

- AN ALTERNATIVE WHEN  $Q$  IS KNOWN

$$\dot{P}(t) = P(t)Q(t)$$

WHERE

$P_{(r+1) \times (r+1)}$  IS THE P.T.M.

$Q_{(r+1) \times (r+1)}$  IS THE T.R.M.

$$P_f = [P(t)]_{(1,r+1)}, \quad t \leq t_m$$

- COMPOSITE FAILURE PROBABILITY  
OF  $m$  CASCADED BLOCKS

$$1 - \prod_{i=1}^m \{1 - [P_i(t)]_{(1,r+1)}\}$$

$$Q = \begin{bmatrix} -n\lambda & C_{01}n\lambda & 0 & \cdots & 0 & [1 - C_{01}]n\lambda \\ 0 & -(n-1)\lambda & C_{12}(n-1)\lambda & 0 & \cdots & [1 - C_{12}](n-1)\lambda \\ \vdots & 0 & \ddots & \ddots & \ddots & \vdots \\ 0 & \cdots & 0 & \cdots & -(n-r+1)\lambda & (n-r+1)\lambda \\ 0 & \cdots & \cdots & \cdots & 0 & 0 \end{bmatrix}$$

- $Q$  INDEPENDENT OF  $t$

$\Rightarrow$  HOMOGENEOUS MARKOV PROCESS

$$\begin{aligned} P(t) &= e^{Qt} \\ &= P^N\left(\frac{t}{N}\right) \\ &\approx \left(I + Q\frac{t}{N}\right)^N, \quad \text{EULER APPROXIMATION} \\ &\approx (I + Qt), \quad \text{TAYLOR EXPANSION} \end{aligned}$$

$$\begin{aligned} P_f &= [P(t_m)]_{(1,r+1)} \\ &\approx [Q]_{(1,r+1)} t_m \\ &= [1 - C_{01}]n\lambda t_m \end{aligned}$$



• APPROXIMATION ERROR

$$\begin{aligned} P_f(t) &= [P(t)]_{1,r+1} \\ &= [e^{Qt}]_{1,r+1} \\ &= \lim_{N \rightarrow \infty} \sum_{i=0}^N \frac{1}{i!} [(Qt)^i]_{1,r+1} \end{aligned}$$

DEFINE THE APPROXIMATION ERROR

$$e = P_f(t) - P_f^{approx.}(t)$$

THEN

$$e(t) = \lim_{N \rightarrow \infty} \sum_{i=2}^N \frac{1}{i!} [(Qt)^i]_{1,r+1}$$

NOTE THAT

$$|[(Qt)^i]_{1,r+1}| \leq (r+1)(n\lambda t)^i$$

THEREFORE

$$\begin{aligned} |e| &\leq \lim_{N \rightarrow \infty} \sum_{i=2}^N \frac{1}{i!} (r+1)(n\lambda t)^i \\ &\leq \frac{(r+1)(n\lambda t)^2}{2} \lim_{N \rightarrow \infty} \sum_{i=0}^{N-2} \left(\frac{n\lambda t}{2}\right)^i \\ &= \frac{(r+1)(n\lambda t)^2}{2 - n\lambda t}, \quad n\lambda t < 2 \\ &< (r+1)(n\lambda t)^2, \quad n\lambda t < 1 \end{aligned}$$

• SOME REMARKS

◦ GOOD APPROXIMATION

$$(r+1)(n\lambda t)^2 \ll (1 - C_{01})n\lambda t$$

OR

$$C_{01} < 1 - n^2\lambda t$$

◦ REDUNDANT SYSTEM VERSUS SIMPLE SYSTEM

$$[1 - C_{01}]n\lambda t_m < \lambda t_m$$

OR

$$C_{01} > 1 - \frac{1}{n}$$

◦ IN GENERAL,  $1 - C_{01}$  DECREASES AS  $n$  INCREASES

$\Rightarrow$  THERE IS AN  $n$  AT WHICH

$$\min_n (1 - C_{01})n\lambda t_m$$

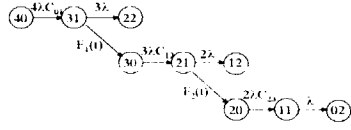
IS ACHIEVED

◦ EXAMPLE

REDUNDANCY MANAGEMENT	$n$	$C_{01}$	$(1 - C_{01})n$
VOTING	4	0.992	0.032
VOTING	3	0.99	0.03
COMPARING	2	0.89	0.22

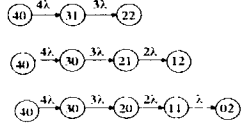
• ERROR DUE TO NEGLECTING REMOVAL TIMES

◦ OMITTED PATHS TO DEATH STATES



◦ HIGHER RATES TO DEATH STATES

$$-C_{i,i+1} \leftarrow 1, F_i(t) \leftarrow 1$$



◦ APPROXIMATION ERROR BOUND

$$\begin{aligned} e &= p_f - p_f^{approx.} < \sum_{j=1}^3 \prod_{i=1}^{5-j} (5-i)(1 - e^{-\lambda t}) e^{-(4-i)\lambda t} \\ &\leq \sum_{j=1}^3 \prod_{i=1}^{5-j} (5-i)\lambda = 4 \cdot 3\lambda^2 t (2 \cdot \lambda^2 t^2 + 2 \cdot \lambda t + 1) \\ &< (4\lambda t)^2, \quad (\lambda t) < \frac{1}{8} \end{aligned}$$

◦ GOOD APPROXIMATION

$$(1 - C_{01})4\lambda t \gg (4\lambda t)^2 \Leftrightarrow C_{01} \ll 1 - 4\lambda t$$

• GENERAL ERROR BOUND FOR NEGLECTING REMOVAL TIMES

$$\begin{aligned} e &= p_f - p_f^{approx.} < \sum_{i=2}^r \frac{n!}{(n-i)!} (1 - e^{-\lambda t})^i e^{-\frac{i}{2}(2n-i-1)\lambda t} \\ &< \sum_{i=2}^r \frac{n!}{(n-i)!} (\lambda t)^i - n(n-1)(\lambda t)^2 \sum_{i=0}^{r-2} [(n-2)\lambda t]^i \\ &= n(n-1)(\lambda t)^2 \frac{1 - [(n-2)\lambda t]^{r-1}}{1 - [(n-2)\lambda t]} \\ &< (n\lambda t)^2, \quad n\lambda t < \frac{1}{n-2} \end{aligned}$$

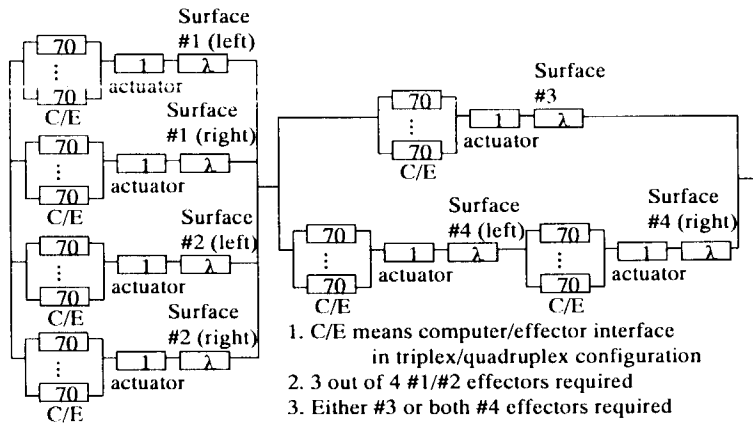
◦ GOOD APPROXIMATION

$$(1 - C_{01})n\lambda t \gg (n\lambda t)^2$$

OR

$$C_{01} \ll 1 - n\lambda t$$

• ANALYSIS OF THE EFFECTOR BLOCK

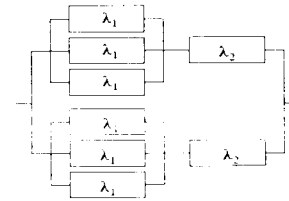


• SURE AND ASSIST ARE NEEDED IN HIGH COVERAGE MODELS

◦ A SIMPLE CASE STUDY

• EXAMPLE: DEGRADABLE 2-PLEX CONTAINING 3-PLEX-1-PLEX'S

$$\lambda_1 = 10^{-5}, \lambda_2 = 5.0 \times 10^{-6}, t_m = 1.0$$



$$C_{01}^1 \in [0.99, 1.0]$$

$$C_{12}^1 \in [0.95, 1.0]$$

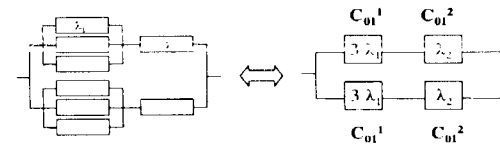
$$C_{23}^1 \in [0.90, 1.0]$$

$$C_{01}^2 \in [0.99, 1.0]$$

◦ A SIMPLIFICATION WITH AN EQUIVALENT FIRST ORDER EFFECT

—  $3\lambda_1$  AND  $\lambda_2$  ARE OF THE SAME ORDERS OF MAGNITUDE

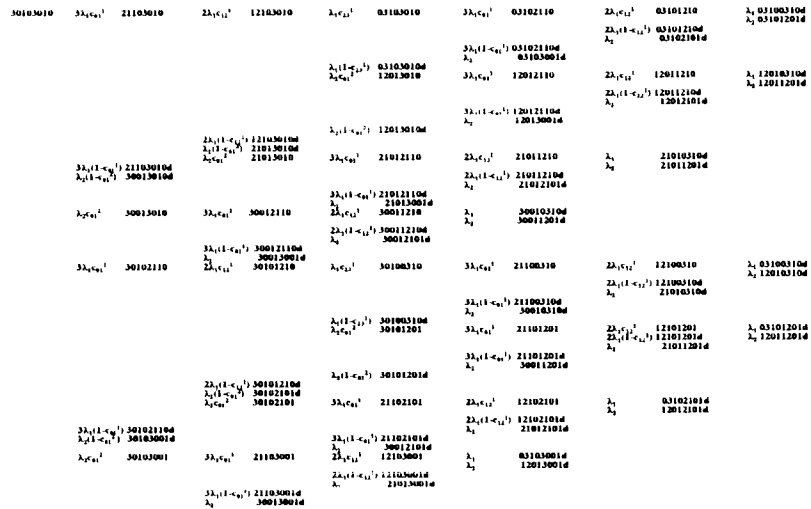
—  $C_{01}^1$  AND  $C_{01}^2$  ARE OF THE SAME ORDERS OF MAGNITUDE



◦ SIMPLE FORMULA

$$P_f = 6\lambda_1[1 - C_{01}^1]t + 2\lambda_2[1 - C_{01}^2]t, \quad t \leq t_m$$

## ○ STATE TRANSITION DIAGRAM



## ● USING ASSIST AND SURE

```
(* Markov model generation for a 2-channel 3-plex--1-plex degradable configuration *)
(* Failure rates and coverages *)
LA=1.0E-5; (* subsystem failure rate for block A (3-plex block) *)
LB=5.0E-6; (* subsystem failure rate for block B (1-plex block) *)
CA01=0.99; (* coverage for the 1st failure in block A *)
CA12=0.95; (* coverage for the 2nd failure in block A *)
CA23=0.90; (* coverage for the 3rd failure in block A *)
CB01=0.99; (* coverage for the failure in block B *)
(* input to SURE for coverage variation *)
"DELTA = 0.0 TO+ 1.0;" (* Delta times the coverage range = step size *)
DOORS 100;
CA01 = .99+DELTA*(1.0-0.99); (* CA01 ranges from 0.99 to 1.0 *)
"CA12 = 0.95+DELTA*(1.0-0.95);" (* CA12 ranges from 0.95 to 1.0 *)
"CA23 = 0.90+DELTA*(1.0-0.90);" (* CA23 ranges from 0.90 to 1.0 *)
"CB01=CA01;" (* CB01 ranges from 0.99 to 1.0 *)
(* State space definition. (Array of two identical channels) *)
SPACE=(NCA: ARRAY[1..2] OF 0..3, (* NCA: Number of operative subsystems in block A *)
NFA: ARRAY[1..2] OF 0..3, (* NFA: Number of inoperative subsystems in block A *)
NUA: ARRAY[1..2] OF 0..1, (* NUA: Flag uncovered failures in block A when NUA=1 *)
NCB: ARRAY[1..2] OF 0..1, (* NCB: Number of operative subsystems in block B *)
NFB: ARRAY[1..2] OF 0..1); (* NFB: Number of inoperative subsystems in block B *)
(* Initial state definition *)
START = (2 OF 3, 2 OF 0, 2 OF 0, 2 OF 1, 2 OF 0); (* NCA[1]=3, NFA[1]=0, NUA[1]=0, NCB[1]=1, NFB[1]=0, I=0,1 *)
(* Death state definition *)
DEATHIF (NFA[1]+NFA[2]>5) (* At least one of block A or block B in each channel is inoperative *)
OR (NFA[1]+NFB[2]>3)
OR (NFA[1]+NFB[2]>3)
OR (NFB[1]+NFB[2]>1)
OR (NUA[1]+NUA[2]>1); (* Or any uncovered failures *)
(* State transitions in channel I, I=1,2 *)
FOR I IN 1, 2;
IF (NFB[I]=0) AND (NFA[I]=0) THEN (* 1st failure in block A *)
  TRANTO NCA[I]=NCA[I]-1, NFA[I]=NFA[I]+1, NUA[I]=0 BY NCA[I]*LA*CA01; (* covered *)
  TRANTO NCA[I]=NCA[I]-1, NFA[I]=NFA[I]+1, NUA[I]=1 BY NCA[I]*LA*(1-CA01); (* uncovered *)
ENDIF;
IF (NFB[I]=0) AND (NFA[I]=1) THEN (* 2nd failure in block A *)
  TRANTO NCA[I]=NCA[I]-1, NFA[I]=NFA[I]+1, NUA[I]=0 BY NCA[I]*LA*CA12; (* covered *)
  TRANTO NCA[I]=NCA[I]-1, NFA[I]=NFA[I]+1, NUA[I]=1 BY NCA[I]*LA*(1-CA12); (* uncovered *)
ENDIF;
IF (NFB[I]=0) AND (NFA[I]=2) THEN (* 3rd failure in block A *)
  TRANTO NCA[I]=NCA[I]-1, NFA[I]=NFA[I]+1, NUA[I]=0 BY NCA[I]*LA*CA23; (* covered *)
  TRANTO NCA[I]=NCA[I]-1, NFA[I]=NFA[I]+1, NUA[I]=1 BY NCA[I]*LA*(1-CA23); (* uncovered *)
ENDIF;
IF (NCB[I]=1) AND (NCA[I]>0) THEN (* Failure in block B *)
  TRANTO NUA[I]=0, NCB[I]=NCB[I]-1, NFB[I]=NFB[I]+1 BY NCB[I]*LB*CB01; (* covered *)
  TRANTO NUA[I]=1, NCB[I]=NCB[I]-1, NFB[I]=NFB[I]+1 BY NCB[I]*LB*(1-CB01); (* uncovered *)
ENDIF;
ENDFOR;
```

## ○ FINITE REMOVAL TIMES CAN BE EASILY INCORPORATED

◦ ANALYTIC MODEL WITH MINIMAL STATE DIMENSION

$$\dot{P}(t) = P(t)Q(t), \quad P(0) = I$$

AND  $Q$  IS GIVEN BY

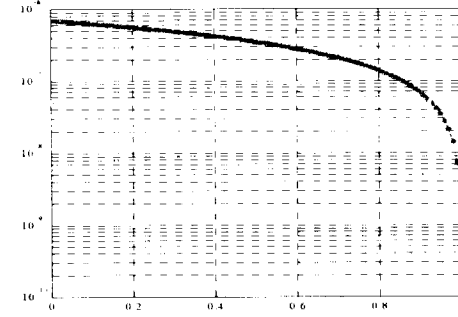
$$\begin{bmatrix} -6\lambda_1 - 2\lambda_2 & 6\lambda_1 C_{01}^1 + 2\lambda_2 C_{01}^2 & 0 & 0 \\ 0 & -10\lambda_1 - 4\lambda_2 & 4\lambda_1 C_{12}^1 + 6\lambda_2 C_{01}^1 + 2\lambda_2 C_{01}^2 & 0 \\ 0 & 0 & -12\lambda_1 - 6\lambda_2 & 2\lambda_1 C_{23}^1 + 4\lambda_1 C_{12}^1 + 6\lambda_1 C_{01}^1 + 2\lambda_2 C_{01}^2 \\ 0 & 0 & 0 & -18\lambda_1 - 8\lambda_2 \\ 0 & 0 & 0 & 0 \\ 0 & 0 & 0 & 0 \\ 0 & 0 & 0 & 0 \end{bmatrix}$$

$$\begin{bmatrix} 0 & 0 & 6\lambda_1[1 - C_{01}^1] + 2\lambda_2[1 - C_{01}^2] \\ 0 & 0 & 4\lambda_1[1 - C_{12}^1] + 6\lambda_1[1 - C_{01}^1] + 2\lambda_2[1 - C_{01}^2] + 2\lambda_2 \\ 0 & 0 & 2\lambda_1[1 - C_{23}^1] + 2\lambda_2[1 - C_{10}^2] + 6\lambda_1[1 - C_{01}^1] + 4\lambda_1[1 - C_{12}^1] + 4\lambda_2 \\ 12\lambda_1 C_{01}^1 + 4\lambda_1 C_{12}^1 & 0 & 12\lambda_1[1 - C_{01}^1] + 4\lambda_1[1 - C_{12}^1] + 2\lambda_1 + 8\lambda_2 \\ -10\lambda_1 - 6\lambda_2 & 8\lambda_1 C_{12}^1 & 8\lambda_1[1 - C_{12}^1] + 2\lambda_1 + 6\lambda_2 \\ 0 & -4\lambda_1 - 4\lambda_2 & 4\lambda_1 + 4\lambda_2 \\ 0 & 0 & 0 \end{bmatrix}$$

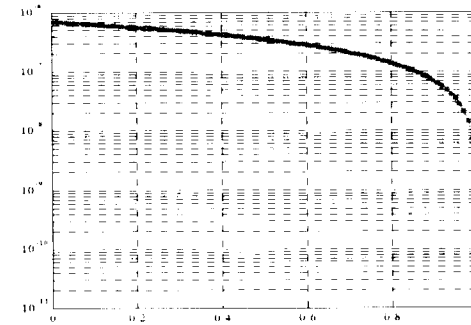
◦ THE ABOVE RESULTS IN THE SAME SIMPLE FORMULA

$$P_f = [P(t)]_{(1,7)} \approx [Q]_{(1,7)} t = 6\lambda_1[1 - C_{01}^1]t + 2\lambda_2[1 - C_{01}^2]t, \quad t \leq t_m$$

◦ EFFECT OF SIMPLIFICATION



◦ MATRIX EXPONENTIAL V.S. ASSIST/SURE



- KEY TO ENHANCED RELIABILITY—HIGH COVERAGE
  - CURRENTLY ACHIEVABLE VALUE IN FTFCS?
    - $1 - C_{01} \approx 10^{-1}$
  - IMPROVEMENT DESIRABLE?
    - REDUCTION OF  $1 - C_{01}$  BY SEVERAL ORDERS OF MAGNITUDE
  - ADEQUATE VALUE?
    - $1 - C_{01} \approx n^2 \lambda t_m$
  - WHEN THE ABOVE IS ACHIEVED
    - SURE** IS NEEDED FOR ACCURACY
    - ASSIST** IS NEEDED FOR MODELING
  - A BY-PRODUCT OF **ASSIST**
    - TRANSITION RATE MATRIX OF A MARKOV PROCESS

## REFERENCES

- [1] Bavuso, Dugan, Trivedi, Rothmann, and Smith, Analysis of typical fault-tolerant architectures using HARP, *IEEE Trans. on Reliability*, vol.R-36, pp 176-185, 1987.
- [2] R.W.Butler, An abstract language for specifying Markov reliability models, *IEEE Trans. on Reliability*, vol.R-35, pp 595-601, 1986.
- [3] R.W.Butler, and A.L.White, SURE reliability analysis: program and mathematics, *NASA Technical Paper 2764*, 1988.
- [4] R.W.Butler, The SURE approach to reliability analysis, *IEEE Trans. Reliability*, vol.41, pp 210-218, 1992.
- [5] Dugan, and Trivedi, Coverage modeling for dependability analysis of fault tolerant systems, *IEEE Trans. Computers*, vol.38, pp 775-787, 1989.
- [6] General Electric Company, *Self-Repairing Digital Flight Control System Study*, Report# AFWAL-TR-88-3007, 1987.
- [7] S.T.Trivedi, *Probability & Statistics with Reliability, Queuing, and Computer Science Applications*, Chapter 6, Prentice Hall, 1982.
- [8] A.L. White, Reliability estimation for reconfigurable systems with fast recovery, *Microelectronics Reliability*, vol.26, pp 1111-1120, 1986.
- [9] Dugan, Trivedi, Smotherman, and Geist, The hybrid automated reliability predictor, *J. Guidance*, vol.9, pp.319-331, 1986.
- [10] N.E.Wu, Hardware reduction through use of control surface redundancy, *Technical report to General Electric Company*, 1991.
- [11] D.L.Isaacson, and R.M.Madsen, *Markov Chains Theory and Applications*, John Wiley & Sons, 1976.